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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/765,267	PAPPIN ET AL.	
Examiner	Art Unit	
Nyeemah Grazier	1626	

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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
STN Structure Search	3/8/2006	NG
STIC Structure and Inventor Name Search	3/10/2006	NG
Classification/Text Search (EAST) Class 544/141,172,372,399; 546/208,238)	3/11/2006	NG
IDS	3/10/2006	NG